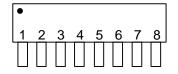
5-TAP, HCMOS-INTERFACED FIXED DELAY LINE (SERIES DDU222C)



FEATURES

- Five equally spaced outputs
- Very narrow device (SIP package)
- Stackable for PC board economy
- Input & outputs fully CMOS interfaced & buffered
- 10 T²L fan-out capability

PACKAGES



VCC IN T1 T2 T3 T4 T5 GND

DDU222F-xx Commercial DDU222F-xxM Military

FUNCTIONAL DESCRIPTION

The DDU222C-series device is a 5-tap digitally buffered delay line. The signal input (IN) is reproduced at the outputs (T1-T5), shifted in time by an amount given by the device dash number. For dash numbers less than 40, the total delay of the line is measured from T1 to T5, with the nominal value given by the dash number. The nominal tap-to-tap delay increment

PIN DESCRIPTIONS

IN Signal Input
T1-T5 Tap Outputs
VDD +5 Volts
GND Ground

is given by 1/4 of this number. The inherent delay from IN to T1 is nominally 8.0ns. For dash numbers greater than or equal to 40, the total delay of the line is measured from IN to T5, with the nominal value given by the dash number. The nominal tap-to-tap delay increment is given by 1/5 of this number.

SERIES SPECIFICATIONS

Minimum input pulse width: 40% of total delay

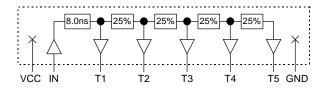
Output rise time: 8ns typical
 Supply voltage: 5VDC ± 5%

Supply current: $I_{CCL} = 40\mu a$ typical

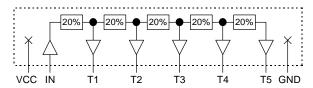
 $I_{CCH} = 10$ ma typical

Operating temperature: 0° to 70° C

Temp. coefficient of total delay: 300 PPM/°C



Functional diagram for dash numbers < 40



Functional diagram for dash numbers >= 40

DASH NUMBER SPECIFICATIONS

Part	Total	Delay Per	
Number	Delay (ns)	Tap (ns)	
DDU222C-10	10 \pm 2.0 *	2.5 ± 1.0	
DDU222C-20	20 \pm 2.0 *	5.0 ± 2.0	
DDU222C-50	50 ± 3.0	10.0 ± 3.0	
DDU222C-60	60 ± 3.0	12.0 ± 3.0	
DDU222C-75	75 ± 4.0	15.0 ± 3.0	
DDU222C-100	100 ± 5.0	20.0 ± 3.0	
DDU222C-125	125 ± 6.5	25.0 ± 3.0	
DDU222C-150	150 ± 7.5	30.0 ± 3.0	
DDU222C-175	175 ± 8.0	35.0 ± 4.0	
DDU222C-200	200 ± 10.0	40.0 ± 4.0	
DDU222C-250	250 ± 12.5	50.0 ± 5.0	

^{*} Total delay is referenced to first tap output Input to first tap = 8.0ns ± 2 ns

NOTE: Any dash number between 10 and 250 not shown is also available.

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APPLICATION NOTES

HIGH FREQUENCY RESPONSE

The DDU222C tolerances are guaranteed for input pulse widths and periods greater than those specified in the test conditions. Although the device will function properly for pulse widths as small as 40% of the total delay and periods as small as 80% of the total delay (for a symmetric input), the delays may deviate from their values at low frequency. However, for a given input condition, the deviation will be repeatable from pulse to pulse. Contact technical support at Data Delay Devices if your application requires device testing at a specific input condition.

POWER SUPPLY BYPASSING

The DDU222C relies on a stable power supply to produce repeatable delays within the stated tolerances. A 0.1uf capacitor from VDD to GND, located as close as possible to the VDD pin, is recommended. A wide VDD trace and a clean ground plane should be used.

DEVICE SPECIFICATIONS

TABLE 1: ABSOLUTE MAXIMUM RATINGS

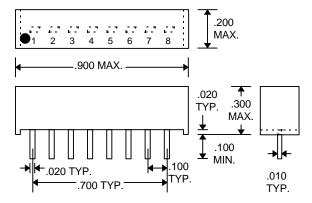
PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
DC Supply Voltage	V_{DD}	-0.3	7.0	V	
Input Pin Voltage	V_{IN}	-0.3	V _{DD} +0.3	V	
Storage Temperature	T_{STRG}	-55	150	С	
Lead Temperature	T_{LEAD}		300	С	10 sec

TABLE 2: DC ELECTRICAL CHARACTERISTICS

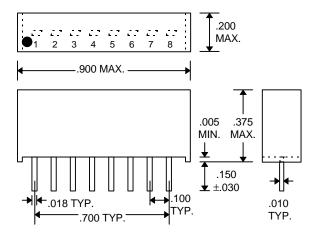
(0C to 70C, 4.75V to 5.25V)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
High Level Output Voltage	V_{OH}	3.98	4.4		V	$V_{DD} = 5.0, I_{OH} = MAX$
						$V_{IH} = MIN, V_{IL} = MAX$
Low Level Output Voltage	V_{OL}		0.15	0.26	V	$V_{DD} = 5.0, I_{OL} = MAX$
						$V_{IH} = MIN, V_{IL} = MAX$
High Level Output Current	I _{OH}			-4.0	mΑ	
Low Level Output Current	I _{OL}			4.0	mA	
High Level Input Voltage	V_{IH}	3.15			V	
Low Level Input Voltage	V_{IL}			1.35	V	
Input Current	I _{IH}			0.10	μΑ	$V_{DD} = 5.0$

PACKAGE DIMENSIONS



DDU222C-xx (Commercial)



DDU222C-xxM (Military)

DELAY LINE AUTOMATED TESTING

TEST CONDITIONS

INPUT: OUTPUT:

Ambient Temperature: $25^{\circ}\text{C} \pm 3^{\circ}\text{C}$ **Load:** 1 FAST-TTL Gate

Supply Voltage (VDD): $5.0V \pm 0.1V$ C_{load}: $5pf \pm 10\%$

Input Pulse: High = $5.0V \pm 0.1V$ Threshold: 2.5V (Rising & Falling) Low = $0.0V \pm 0.1V$

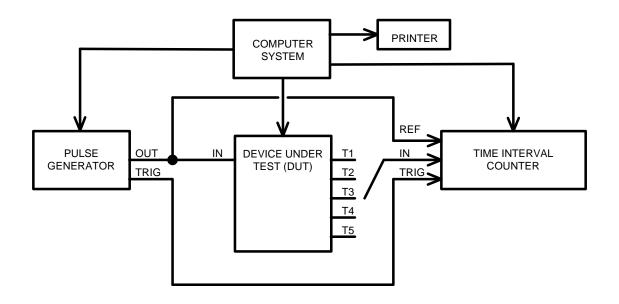
Source Impedance: 50Ω Max.

Rise/Fall Time: 5.0 ns Max. (measured

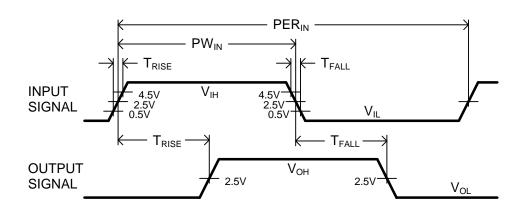
between 0.5V and 4.5V)

Pulse Width: $PW_{IN} = 1.5 \times Total Delay$ **Period:** $PER_{IN} = 10 \times Total Delay$

NOTE: The above conditions are for test only and do not in any way restrict the operation of the device.



Test Setup



Timing Diagram For Testing